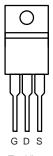


T424CU-VB Datasheet

N-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY				
V _{DS} (V)	30			
$R_{DS(on)}(\Omega)$ at $V_{GS} = 10 V$	0. 0020			
$R_{DS(on)}(\Omega)$ at $V_{GS} = 4.5 V$	0. 0028			
I _D (A)	140			
Configuration	Single			

TO-220AB





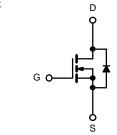
Top View

FEATURES

- DT-Trench Power MOSFET
- 100 % R_g and UIS Tested
- Compliant to RoHS Directive 2011/65/EU

APPLICATIONS

- OR-ing
- Server ٠
- DC/DC



N-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS	S (T _A = 25 °C, unle	ss otherwise not	ted)		
Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V _{DS}	30	V	
Gate-Source Voltage		V _{GS}	± 20	V	
Continuous Drain Current (T _J = 175 °C)	T _C = 25 °C		140 ^{a, e}	A	
	T _C = 70 °C		110 ^e		
	T _A = 25 °C	I _D	39 ^{b, c}		
	T _A = 70 °C		28 ^{b, c}		
Pulsed Drain Current		I _{DM}	370		
Avalanche Current Pulse	L = 0.1 mH	I _{AS}	39		
Single Pulse Avalanche Energy	L = 0.1 MH	E _{AS}	375	mJ	
Continuous Source-Drain Diode Current	T _C = 25 °C		90 ^{a, e}		
	T _A = 25 °C	I _S	3.13 ^{b, c}	— A	
Maximum Power Dissipation	T _C = 25 °C		250 ^a		
	T _C = 70 °C	PD	175	w	
	T _A = 25 °C	r D	3.75 ^{b, c}	VV	
	T _A = 70 °C		2.63 ^{b, c}		
Operating Junction and Storage Temperature Ra	ange	T _J , T _{stg}	- 55 to 175	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Тур.	Max.	Unit	
Maximum Junction-to-Ambient ^{b, d}	$t \le 10 \text{ sec}$	R _{thJA}	32	40	°C/W	
Maximum Junction-to-Case	Steady State	R _{thJC}	0.5	0.6	0/10	

Notes: a. Based on $T_C = 25 \ ^{\circ}C$. b. Surface mounted on 1" x 1" FR4 board.

c. t = 10 sec.
d. Maximum under steady state conditions is 90 °C/W.
e. Calculated based on maximum junction temperature. Package limitation current is 90 A.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						•
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 V, I_{D} = 250 \mu A$	30			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	L _ 250 uA		35		
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 7.5		mV/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$	1.0		3.0	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$			± 100	nA
Zero Gate Voltage Drain Current		$V_{DS} = 30 V V_{GS} = 0 V$			1	
	IDSS	$V_{DS} = 24 \text{ V} \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 55 \text{ °C}$			10	μA
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, \text{ V}_{GS} = 10 \text{ V}$	90			Α
	. ,	V _{GS} = 10 V, I _D = 38.8 A		0.0020		Ω
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 4.5 V, I _D = 37 A		0.0028		
Forward Transconductance ^a	9 _{fs}	V _{DS} = 15 V, I _D = 38.8 A		160		S
Dynamic ^b						
Input Capacitance	C _{iss}			8400		
Output Capacitance	C _{oss}	V _{DS} = 15 V, V _{GS} = 0 V, f = 1 MHz		1725		pF
Reverse Transfer Capacitance	C _{rss}			970		- '
· · · · · ·	Qg	V _{DS} = 15 V, V _{GS} = 10 V, I _D = 38.8 A		171	257	nC
Total Gate Charge		V _{DS} = 15 V, V _{GS} = 4.5 V, I _D = 28.8 A		81.5	123	
Gate-Source Charge	Q _{gs}			34		
Gate-Drain Charge	Q _{gd}			29		
Gate Resistance	R _g	f = 1 MHz		1.4	2.1	Ω
Turn-On Delay Time	t _{d(on)}			18	27	
Rise Time	t _r	$V_{DD} = 15 \text{ V}, \text{ R}_{\text{I}} = 0.625 \Omega$		11	17	1
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 24 \text{ A}, \text{ V}_{\text{GEN}} = 10 \text{ V}, \text{ R}_{\text{g}} = 1 \Omega$		70	105	
Fall Time	t _f			10	15	
Turn-On Delay Time	t _{d(on)}			55	83	ns
Rise Time	t _r	$V_{DD} = 15 \text{ V}, \text{ R}_{1} = 0.67 \Omega$		180	270	1
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 22.5 \text{ A}, \text{ V}_{\text{GEN}} = 4.5 \text{ V}, \text{ R}_{\text{g}} = 1 \Omega$		55	83	-
Fall Time	t _f	-		12	18	
Drain-Source Body Diode Characteristic	s					
Continuous Source-Drain Diode Current	۱ _S	T _C = 25 °C		140		
Pulse Diode Forward Current ^a	I _{SM}			370		A
Body Diode Voltage	V _{SD}	I _S = 22 A		0.8	1.2	V
Body Diode Reverse Recovery Time	t _{rr}			52	78	ns
Body Diode Reverse Recovery Charge	Q _{rr}			70.2	105	nC
Reverse Recovery Fall Time	t _a	$I_F = 20 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 \text{ °C}$		27		
Reverse Recovery Rise Time	t _b			25		ns

Notes:

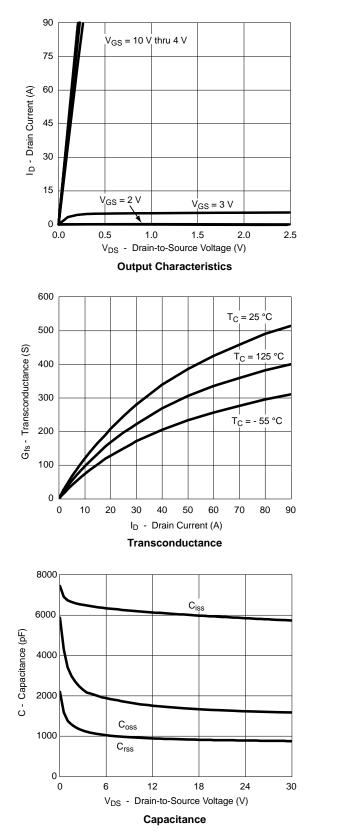
a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %.

b. Guaranteed by design, not subject to production testing.

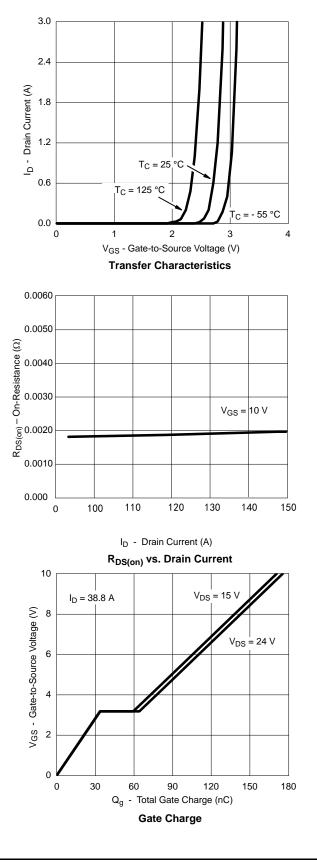
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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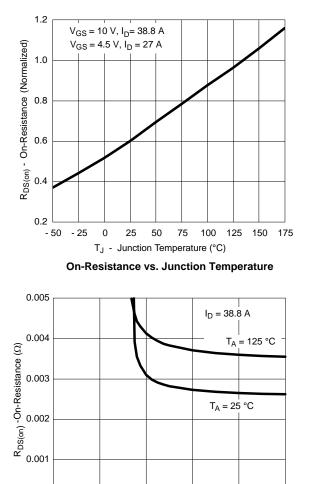


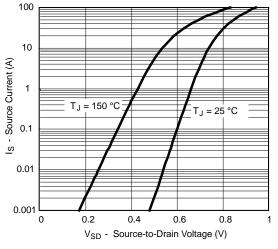
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



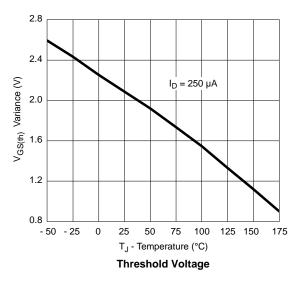


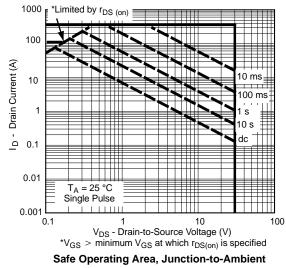






Forward Diode Voltage vs. Temperature





0.000

2

4

6

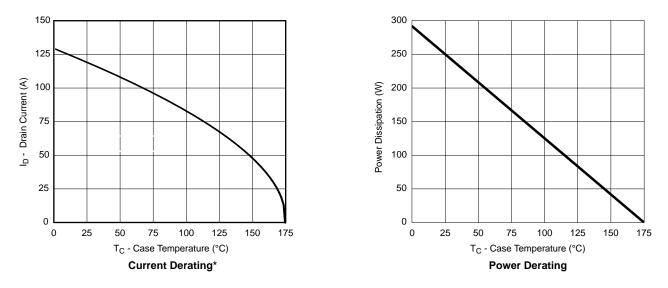
 V_{GS} - Gate-to-Source Voltage (V)

R_{DS(on)} vs. V_{GS} vs. Temperature

8

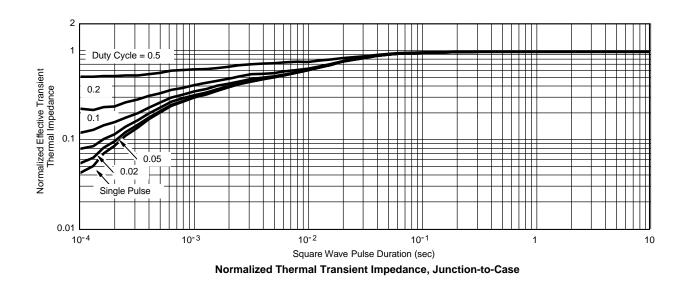
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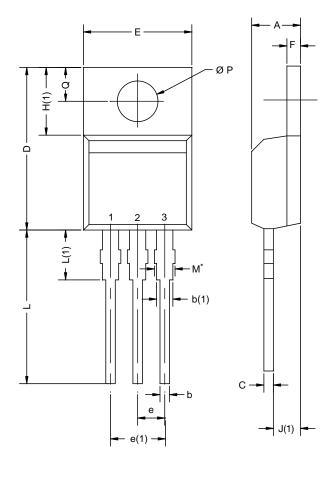
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

*The power dissipation P_D is based on $T_{J(max)} = 175$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





TO-220AB



MIN. 4.25 0.69 1.20	MAX. 4.65 1.01	MIN. 0.167 0.027	MAX. 0.183
0.69 1.20	1.01		0.183
1.20	-	0.027	
		0.027	0.040
	1.73	0.047	0.068
0.36	0.61	0.014	0.024
14.85	15.49	0.585	0.610
10.04	10.51	0.395	0.414
2.41	2.67	0.095	0.105
4.88	5.28	0.192	0.208
1.14	1.40	0.045	0.055
6.09	6.48	0.240	0.255
2.41	2.92	0.095	0.115
13.35	14.02	0.526	0.552
3.32	3.82	0.131	0.150
3.54	3.94	0.139	0.155
2.60	3.00	0.102	0.118
	10.04 2.41 4.88 1.14 6.09 2.41 13.35 3.32 3.54 2.60	10.04 10.51 2.41 2.67 4.88 5.28 1.14 1.40 6.09 6.48 2.41 2.92 13.35 14.02 3.32 3.82 3.54 3.94	10.0410.510.3952.412.670.0954.885.280.1921.141.400.0456.096.480.2402.412.920.09513.3514.020.5263.323.820.1313.543.940.1392.603.000.102

Notes

 * M = 1.32 mm to 1.62 mm (dimension including protrusion) Heatsink hole for HVM



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